



Gaetano **Marrocco** and Stefano **Caizzone**

marrocco@disp.uniroma2.it



Deformation of Structures

Processes in evolution involving structural deformations

- Civil infrastructures
- Cultural heritage
- Aircrafts/ships/vehicles

Multi-point information (map) required

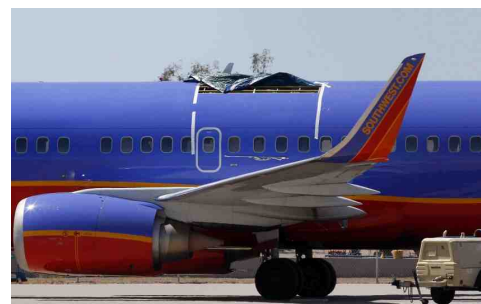
- Control of a large surface
- Detection of unknown defects



Post-Disaster control



Continuous Monitoring Network



Disaster Prevention



Deformation of Structures

Structural Health Monitoring (SHM)

A structure may Fail

- Aging
- Environment
- Accidental events
- Design and manufacturing errors
- Unsatisfactory maintenance

SHM:

*“The process of implementing monitoring strategies to give, at every moment during the life of a structure, a diagnosis of the “**state**” of the constituent **materials**, of the different **parts**, and of the full **assembly** of these parts constituting the structure as a whole.”*



Deformation of Structures

In Numbers

Case	Typical Range	Resolution
Cracks in concrete Beams	1 mm	0.1mm
Cracks in steel reinforced concrete Beams	2-6 mm	0.5mm
Cracks in walls	2-4 mm	0.2mm
Cracks in tunnels' concrete slabs	0.1-0.2 mm	0.05mm
Deformation of foundations	1-10 mm	0.5mm
Cracks in Old and Historic buildings	1+ cm	1-2mm
Deformations in Ground Vibration Testing on Aerospace Structural Models	5cm	0.1mm

Parametrization of Deformation

Stress

$$\bar{S} = \lim_{A \rightarrow 0} \frac{\bar{F}}{A}$$

Displacement Vector

$$\vec{d} = u(x, y, z)\hat{i} + v(x, y, z)\hat{j} + w(x, y, z)\hat{k}$$

Therefore, a point $P(x, y, z)$ will become, after the stress is applied, a new point $P'(x + u, y + v, z + w)$.

Strain

$$\underline{\epsilon} = \begin{vmatrix} \epsilon_x & \epsilon_{xy} & \epsilon_{xz} \\ \epsilon_{yx} & \epsilon_y & \epsilon_{yz} \\ \epsilon_{zx} & \epsilon_{zy} & \epsilon_z \end{vmatrix}$$

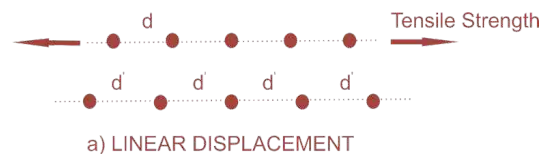
$$\epsilon_x = \frac{\Delta dx}{dx} = \frac{\delta u}{\delta x} \quad \text{Normal strain}$$

Deformation Models

Constant Strain

with Linear Displacement

- All points subjected to the same constant strain.
- Equal-size segments are scaled in a same way during the deformation
- dilatation/compression of unbounded body,
- **crack formation**



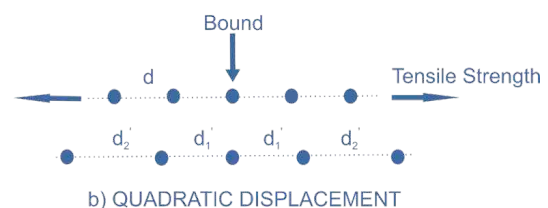
$$u = b_0x + b_1y$$

$$\epsilon_x = \frac{\delta u}{\delta x} = b_0.$$

Linear Strain

with Quadratic Displacement

- Equal-size segments may be transformed in a different way depending on the position over the body
- deformation of bounded bodies,
- **crack growth**



$$u = b_0 + b_1x + b_2y + b_3x^2 + b_4xy + b_5y^2$$

$$\epsilon_x = \frac{\delta u}{\delta x} = 2b_3x$$

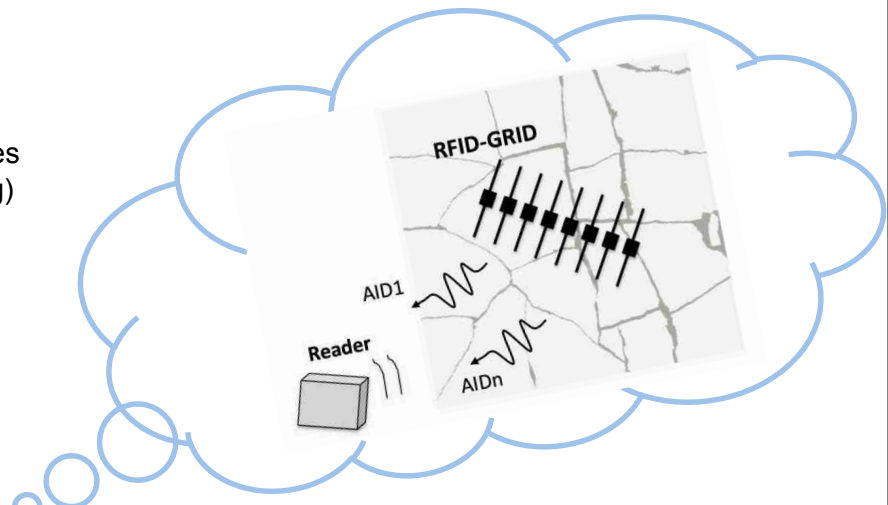
Distributed-Deformation & RFID

RFID may provide

- Wireless reading
- Fully autonomous
- Low-cost
- Deployable in multitudes (i.e. multi-point sensing)



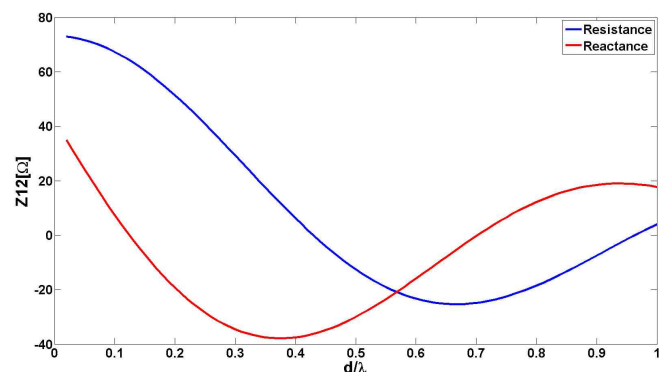
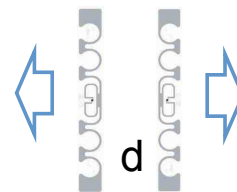
Our vision...



A grid of interacting UHF RFID tags

Physical rationale engineering em. coupling

- Change of mutual distance between two antennas caused by deformation of the surface will produce a variation of the tag's response due to **electromagnetic coupling**
- Change of **active impedance**
- Change of **embedded gain**
- Deformation are **remotely detectable** by a RFID reader



The idea may be extended to an array of tags

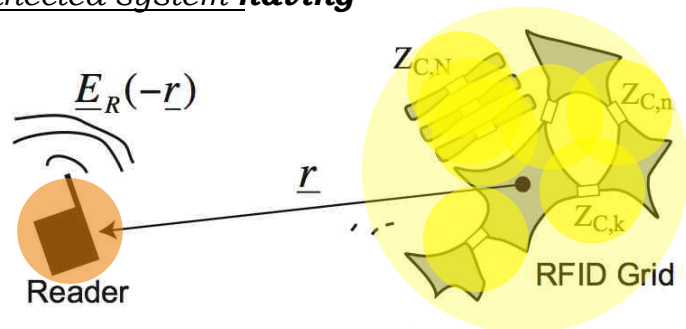
➔ RFID Grids

RFID Grids: multi-chip system

The close displacement of UHF RFID tags can be considered as an electromagnetic interconnected system **having specific properties**

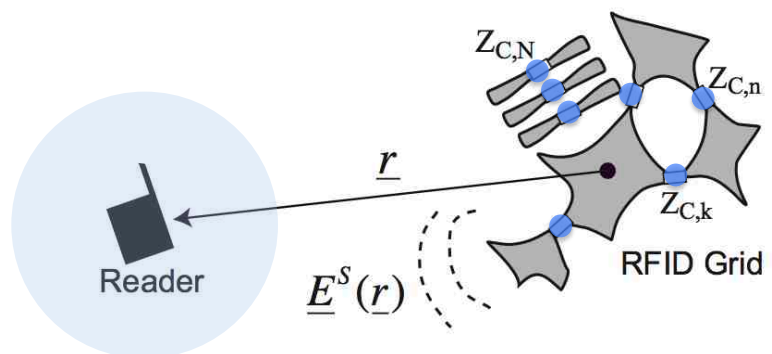
Direct Link (scavenging)

- A highly-coupled coherent system
- not an Array since there is no summation of received signals



Inverse Link (backscattering)

- Anti-collision protocol
- Multi-port scatterer with incoherent modulating loads

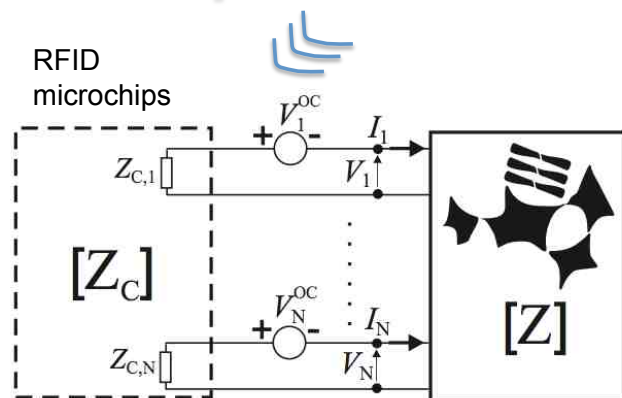


Model: Multi-port scatterer

Radiation / scattering

Embedded effective length & Gain

$$\{h_n(\hat{r}), G_n(\hat{r})\}, \quad n = 1..N$$



Impedances

Network representation

$$\mathbf{I} = -\mathbf{Y}_G \cdot \mathbf{V}^{OC}$$

$$\mathbf{Y}_G = [\mathbf{Z} + \mathbf{Z}_C]^{-1} = [\mathbf{Z}_G]^{-1}$$

Admittance Matrix of the Grid

$$\mathbf{Z}_C = \begin{bmatrix} Z_{C,1}(t) & 0 & 0 & 0 \\ 0 & Z_{C,2}(t) & 0 & 0 \\ 0 & 0 & 0 & 0 \\ 0 & 0 & 0 & Z_{C,N}(t) \end{bmatrix}$$

Grid's Fingerprint

Analog Identifier (AID) of Grid's elements

$$AID_n \equiv \frac{p_n}{2\sqrt{P_{R \leftarrow T_n} P_n^{to}}} = \alpha R_{C,n} |Y_{G,nn}|$$

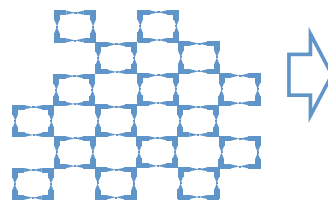
- Angle and position invariant
- Environment invariant
- Frequency dependent

RFID-GRID fingerprint

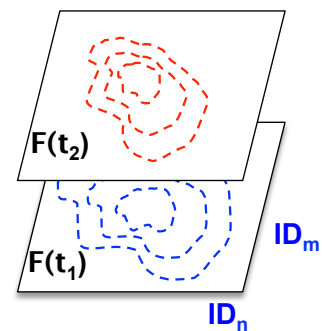
$$\mathbf{F}(\omega) = \begin{bmatrix} \text{analog } AID_1(f) & \text{digital } ID_1 \\ AID_2(f) & ID_2 \\ \vdots & \vdots \\ AID_N(f) & ID_N \end{bmatrix}$$

A tool to obtain a multi-dimensional map of the surface deformation

Grid over surface



Deformation map



G. Marrocco, "RFID GRIDS: Part I – Electromagnetic Theory", *IEEE Trans. Antennas Propagat.*, March. 2011
S. Caizzone, G. Marrocco, "RFID GRIDS: Part II – Experimentations", *IEEE Trans. Antennas Propagat.* Aug.2011

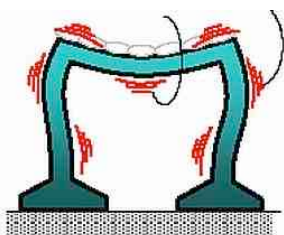
An Inverse Problem

The application of RFID-grid concept to the deformation observation requires the (measured) **variation of AID to be related to** (unknown) change of **inter-element spacing or distributed strain**



Cracks \leftrightarrow displacement

$$\vec{d} \Leftarrow f[\mathbf{F}(\omega)]$$



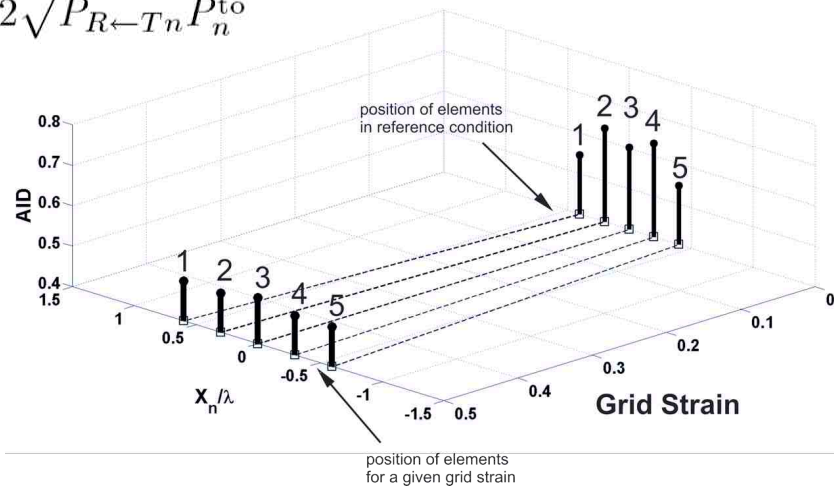
Structural deformations \leftrightarrow strain

$$\varepsilon \Leftarrow f[\mathbf{F}(\omega)]$$

Processing The RFID Fingerprint

AID histogram pattern

$$F_n \equiv \frac{p_n}{2\sqrt{P_{R \leftarrow T_n} P_n^{to}}}$$



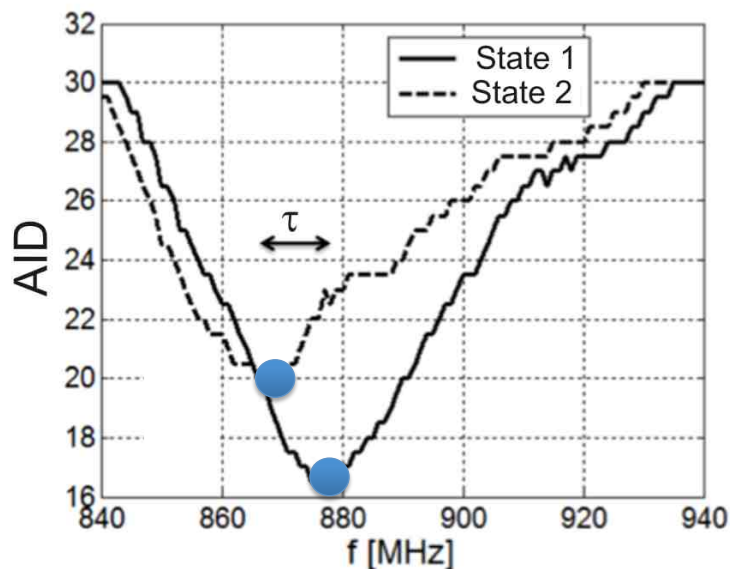
A visual relationship between the change in the geometrical position of the tags and the corresponding modification of each AID_n as a function of the grid strain, defined as the **incremental change in the length of the whole grid**

Processing The RFID Fingerprint

Frequency-domain Indicator

Frequency shift

$$\tau_n = k\Delta f : \sum_{m=1}^M AID_{nm}^{(0)} AID_{n,m-k} \text{ is maximum}$$





- Theoretical formulas for mutual impedance of **side-by-side dipoles**
- Self impedance of standalone configuration

$$Z = \begin{bmatrix} Z_s & Z_{12}(d_{12}) & Z_{13}(d_{13}) & \dots & Z_{1n}(d_{1n}) \\ Z_{21}(d_{21}) & Z_s & Z_{23}(d_{23}) & \dots & Z_{2n}(d_{2n}) \\ \vdots & \vdots & \vdots & \ddots & \vdots \\ Z_{m1}(d_{m1}) & Z_{m2}(d_{m2}) & Z_{m3}(d_{m3}) & \dots & Z_{mn}(d_{mn}) \end{bmatrix}$$

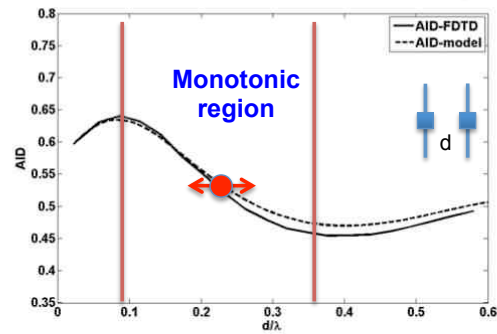
$$Z_{mn} = \frac{\eta}{2\pi} (-2E_i(ju_0) + E_i(ju_1) + E_i(ju_2))$$

E_i : Exponential function

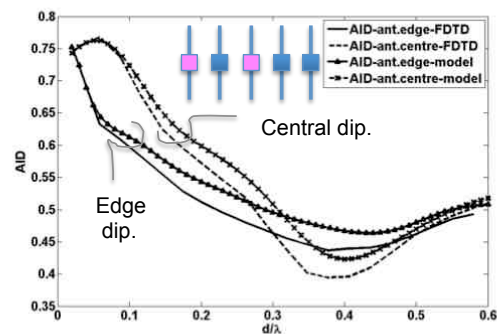
$$AID_n = R_{C,n} |Y_{G,nn}|$$

GRID Model

“mathematical” dipoles



a)



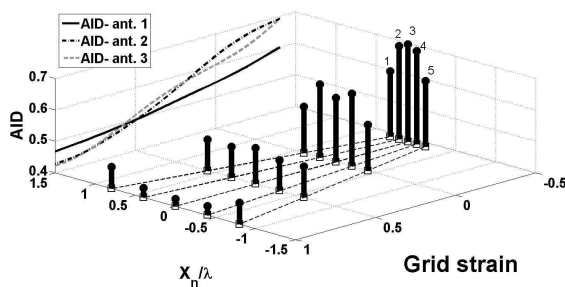
b)

Monotonic region

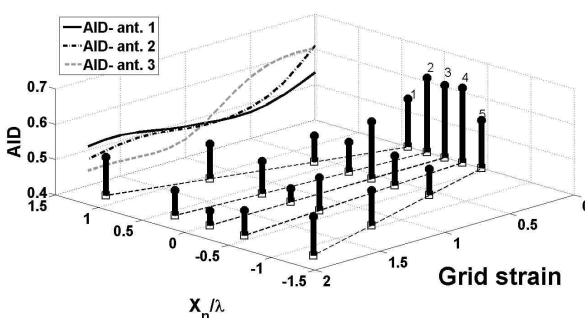


Examples:

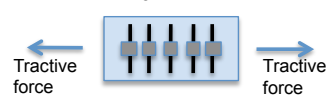
5-elements GRID (“mathematical” dipoles)



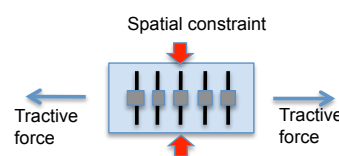
$f=870 \text{ MHz}$



$$d_0 = 0.2\lambda$$



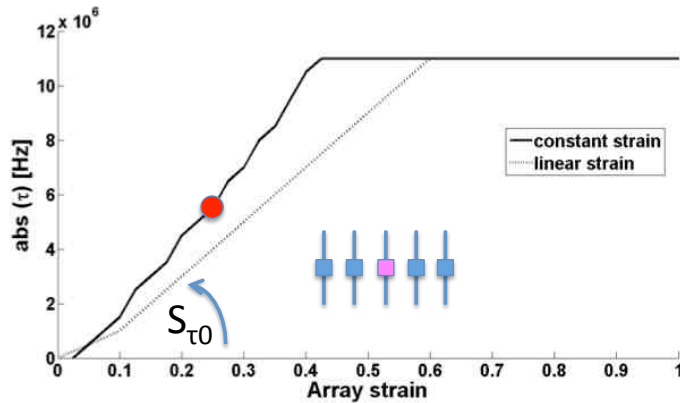
Constant strain



Linear strain



Examples: 5 elements GRID – frequency shift



Sensitivity (w.r.t strain)

$$S_{\tau} = \frac{\partial \tau}{\partial \varepsilon} \quad \text{frequency shift sensitivity}$$

$$S_{\tau_0} (\text{constant strain}) = 26 \text{ MHz} / \varepsilon$$

$$S_{\tau_0} (\text{linear strain}) = 20 \text{ MHz} / \varepsilon$$

Frequency shift of the **central element** versus **strain** of the overall grid

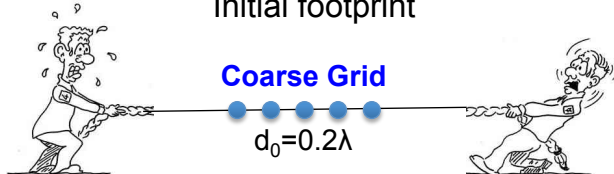
Example

A measured frequency shift of **250KHz** in the tags' response will indicate a strain of **1%** of the object (elongation of 1% of the overall grid size)

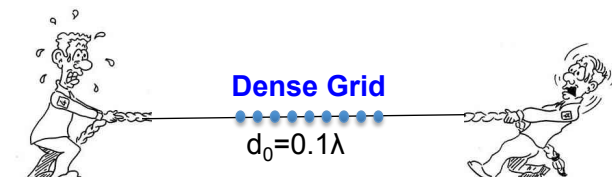


Examples: dense and coarse grids

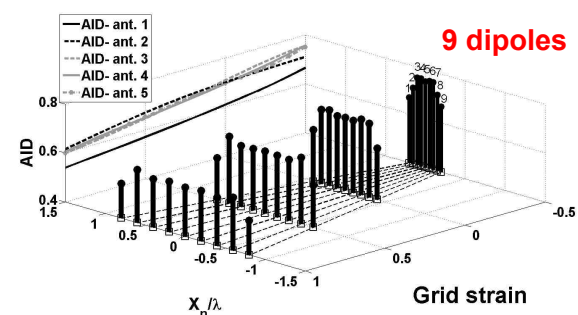
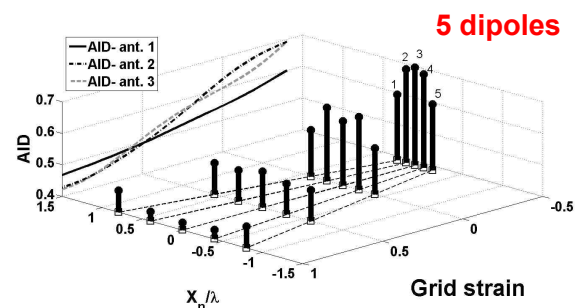
A same
Initial footprint



$$f = 870 \text{ MHz}$$



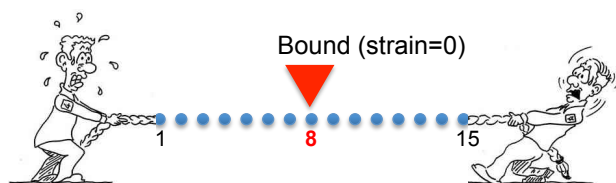
Increasing the grid density reduces the sensitivity to deformation



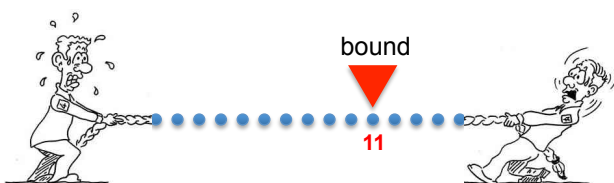
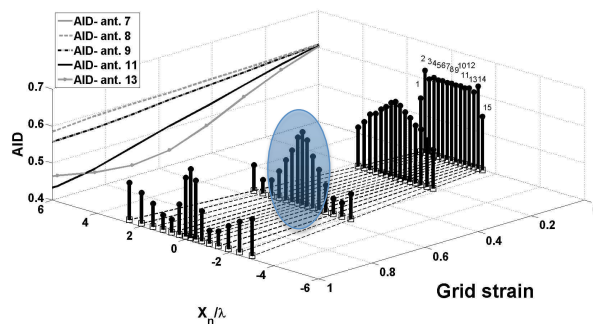


Examples:

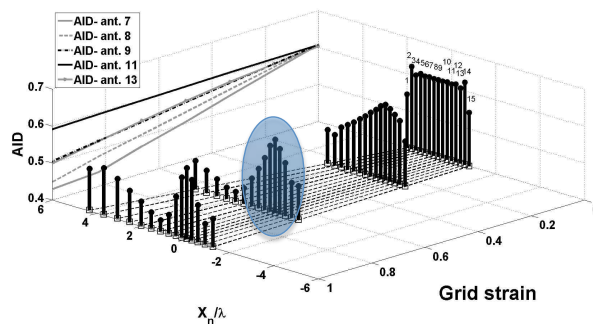
15 elements GRID: *detection of defect*



$$f=870 \text{ MHz} \quad d_0=0.2\lambda$$

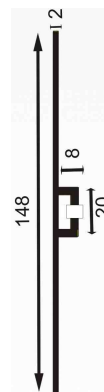
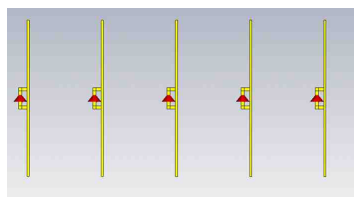


Possibility to **detect** the **position of a crack**

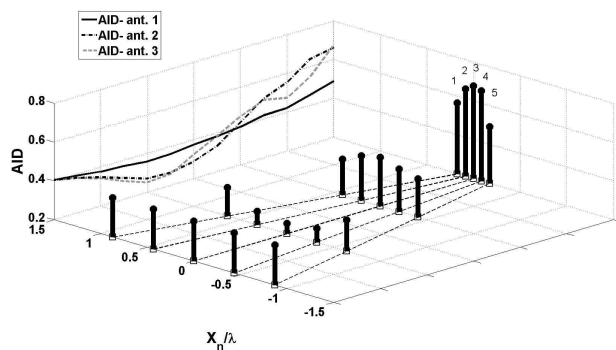


Examples:

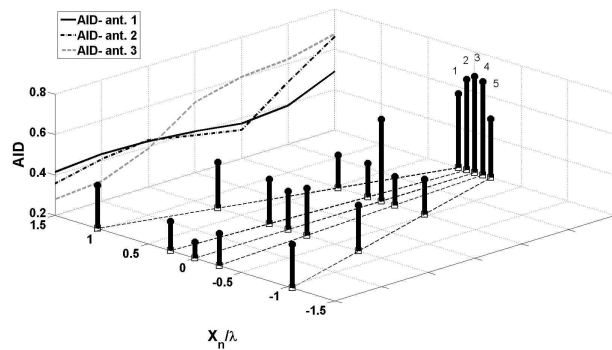
T-match dipoles (FDTD)



Constant strain



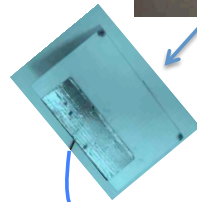
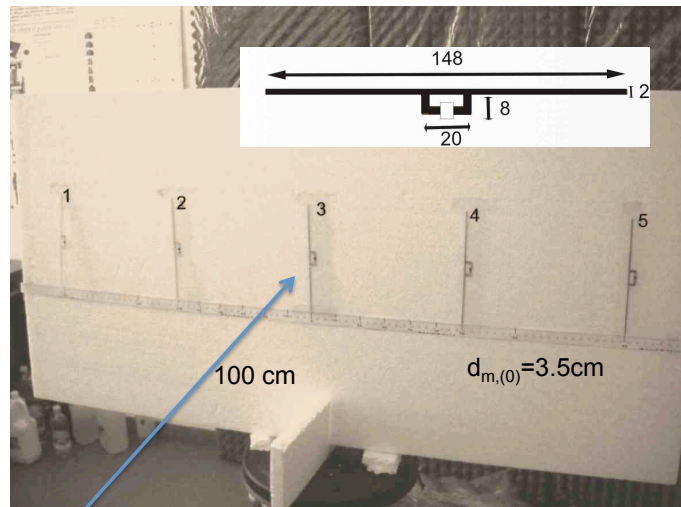
Linear strain



Experiment

Five T-match dipoles

- The grid lays over a foam-like substrate.
- ThingMagic M5E reader + broad band PIFA antenna in broadside orientation at distance, $L=100\text{cm}$
- The positions of the tags inside the grid **are manually changed** in order to simulate a **linear displacement** (compression and elongation).
- Initial condition (zero strain)
- inter-tag distance $d_m=3.5\text{cm}$ (0.2λ at 870MHz).

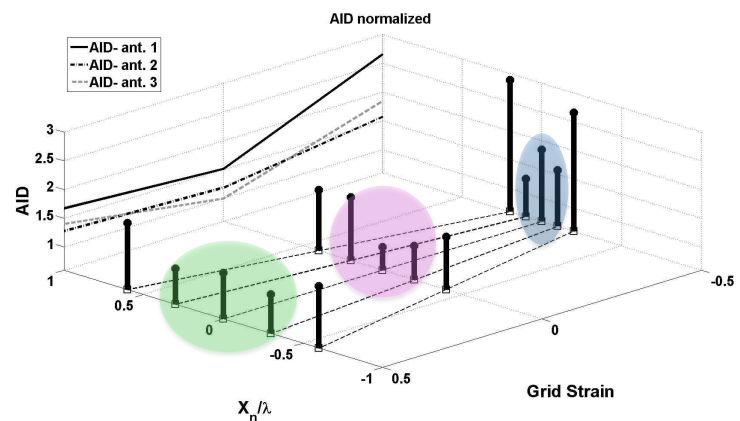
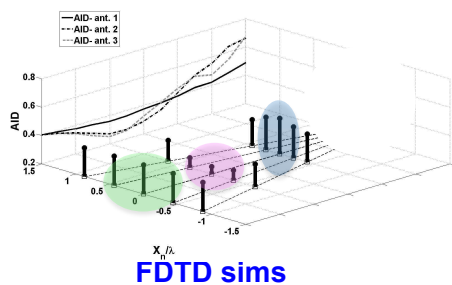


Thingmagic M5E reader

Experiment

Five T-match dipoles

AID bars



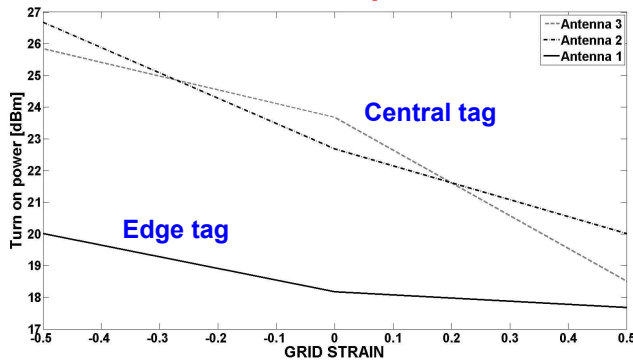
Measurements

Edge elements behaves differently than simulations since FDTD model does not account for the non-linearity of microchip impedances



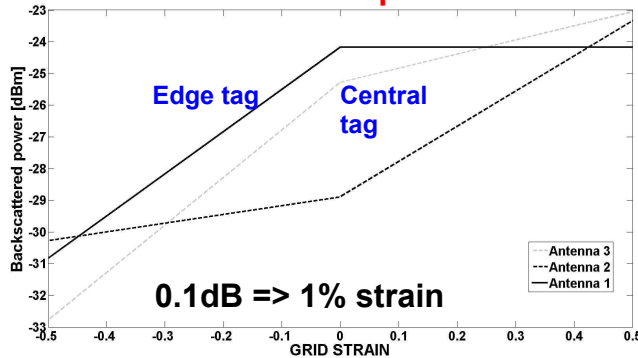
Experiment power metrics

Turn-on power vs strain



- These indicators show a remarkable sensitivity
- The response is not invariable with observation angle

Backscattered power vs strain



Sensitivity-Central tag

$$S(\text{backscatt}) = 9.7\text{dB} / \varepsilon$$

$$S(\text{turn-on}) = 7.3\text{dB} / \varepsilon$$



Discussion

Sensing vs. reader's resolution

Example:

$N=5$

$d_0=5.5\text{cm}$ (initial inter-antenna distance)

Strain: constant

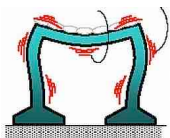
Achieved GRID Sensitivity

$$\Delta p_{BS,\min} \leq S_{BS} \cdot \varepsilon_{\min}$$

$$\Delta p_{BS,\min} \leq S_{BS} \cdot \frac{\Delta d}{d_0}$$



cracks



deformations

Desired system resolution	AID $S_t=25\text{MHz}/\varepsilon$	Backscattering $S_{BS}=10\text{dB}/\varepsilon$
$\Delta d_{\min}=0.1\text{mm}$ Aerospace Structures, cracks in concrete	Reader resolution: $\Delta f_{\min} < 40\text{kHz}$	Reader resolution $\Delta p_{\min} < 0.015\text{ dB}$
$\Delta d_{\min}=1\text{mm}$ cracks in historical buildings	$\Delta f_{\min} < 400\text{ kHz}$	$\Delta p_{\min} < 0.15\text{dB}$
$\varepsilon_{\min}=0.1\%$	Reader resolution: $\Delta f_{\min} < 25\text{ kHz}$	Reader resolution $\Delta p_{\min} < 0.01\text{dB}$
$\varepsilon_{\min}=1\%$	$\Delta f_{\min} < 250\text{kHz}$	$\Delta p_{\min} < 0.1\text{dB}$



Conclusion

- **RFID grids' fingerprint might be a promising tool to**
 - estimate the **overall amount** of surface deformation
 - provide **a local representation of the displacement**
 - identify **defects**
- Other indicators, such as **turn-on power or backscattered power**, can **provide bigger variation levels**, but need fixed setups
- **Grid-spacing controls the sensitivity** (coarse grids are better, provided that tags' response lay in the monotonic region)
- The Grid sensitivity may be improved by investigate **more-coupled lattices** (physically interconnected system)
- **Phase-change** may be also considered thanks to new readers
- **Sensing-oriented readers ($\Delta p \leq 0.1\text{dB}$)** and ad-hoc processing tools are required to form a true imaging system